


<b>Search Notes</b>  	<b>Application/Control No.</b>  09925397	<b>Applicant(s)/Patent Under Reexamination</b>  CHANG ET AL.
	<b>Examiner</b>  Ehichioya, Fred I	<b>Art Unit</b>  2162

SEARCHED			
Class	Subclass	Date	Examiner
707	2 , 3, 5, 10, 104.1	6/8/2009	FE
709	224	6/8/2009	FE

SEARCH NOTES		
Search Notes	Date	Examiner
IEEE Xplore	12/16/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	12/17/07	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	6/24/08	FE
Google.com	6/24/08	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).text search only	2/23/2009	FE
Google Search	2/20/2009	FE
Consulted with Tod Swann (TQAS)	6/1/2009	FE
East (US-PGPub, USPat, EPO, JPO, Derwent).inventor name search, class/subclass and text search	6/8/2009	FE
NPL Multi-Search (ACM, IEEE, INSPEC, ProQuest ... )	6/8/2009	FE
Google Patent Search	6/8/2009	FE

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner
707	104.1	6/8/2009	FE
709	224	6/8/2009	FE

/FRED I EHICHIOYA/ Examiner.Art Unit 2156	
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